## Notice of References Cited Application/Control No. 10/587,272 Applicant(s)/Patent Under Reexamination NEVALAINEN ET AL. Examiner QUN SHEN Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,055,595 A	04-2000	Tachibana et al.	710/301
*	В	US-6,539,476 B1	03-2003	Marianetti et al.	713/100
*	С	US-2004/0254014 A1	12-2004	Quraishi et al.	463/029
*	D	US-2005/0169073 A1	08-2005	Cook et al.	365/202
*	Е	US-7,137,564 B2	11-2006	Chen et al.	235/492
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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